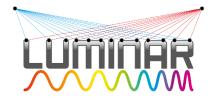




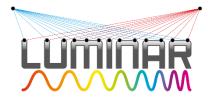
LUMINAR workshop 18-19 May 2016

Wrap-up and discussion



- Novel technology solutions with cost and performance between photogrammetry & laser trackers, ideally operating within 10 m x 10 m x 10 m volume to 50 µm accuracy.
 - ✓ FSI and InPlanT systems (new concepts)
 - ✓ Compensating 3D laser meter
 - ✓ Compensating telemeter
 - ✓ Digital CENTRAX, refraction network

Additional new concepts ?



- Show how absolute distance meters (ADMs) can be made directly traceable to the SI, for example, through the use of quantum reference standards.
 - ✓ FSI HCN cell
 - ✓ Compensating 3D laser meter (iodine reference)
 - Compensating telemeter (frequency reference)

Other systems requiring traceability provision e.g. laser radar, photogrammetry.



- Reference algorithms/software for the analysis of 3D networks of points/point cloud data that are robust, fast, verified, and provide metrologically sound outputs with rigorous uncertainties.
 - Not yet tackled.
 - Still valid issues.



- Understand and predict the behaviour of multi-component assemblies in varying industrial environments, e.g. target of 5 m structures; 5 °C temperature deviation (temporal and spatial).
 - ✓ Hybrid model developed in LUMINAR
 - ✓ Continues in Light Controlled Factory

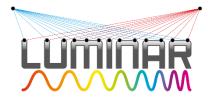
Additional complexity needed.

Tolerance stack up needs to be designed-in.



- On-line compensation for refractive index effects in ambient air in industrial environments ideally to 10⁻⁷, over typical factory spatial volumes (*e.g.* 10 m x 10 m x 5 m).
 - ✓ Compensation in 3D laser meter
 - ✓ Compensation in telemeter
 - ✓ Refraction built into photogrammetry network
 - ✓ Digital CENTRAX and multi-spectral imaging

Simultaneous 3D over entire volume – not yet. And high accuracy will be needed (but some systems not sensitive).



 Better understanding and methods for performance verification of LVM tools bringing traceability through rigorous uncertainty evaluation, including the use of Virtual instruments.

Not yet tackled.

Still valid.



- Understand the dynamic behaviour of LVM tools and provide new methods/tools which can be used to improve the dynamics of time consuming processes.
 - ✓ Research work from Thomas at KIT on laser trackers

Understanding other systems needed. Feedback into processes & process control.



• The following slides are a capture of the discussions at the workshop.



Importance of temperature distribution in measurement

- Distribution of temperature in volume important
- Develop image based i.e. optical based solutions for <u>length</u> metrology rather than <u>surveying</u>, e.g. room sized refractive index and refraction compensation
- Previous research e.g. Williams at NPL, could be re-visited
- Alternatively, refine the spectroscopic technique used in SIB60 by MIKES for shorter range
- Acoustic techniques?
- Refraction modelling and updated refractive index data and equations



Linking & improving of networks

- Richer network adjustment with bigger redundancy
- Helps to include more instruments
- Compatibility of data between instruments (including uncertainties and covariance matrices)
- Adding of ambient information (conventional and optical environmental sensors)
- Different types of devices as parts of the network including FEA modelling

Software

- Reference software e.g. network solvers
- Virtual machines (Monte Carlo)
- Instrument position optimisation for line of sight issues



Equipment

- Many techniques relying on n=2 glass balls
- Difficult to obtain in small quantities
- Consolidated product ordering, alternative targets
- Switch to targetless metrology
- Laser radar not achieve critical mass unlike trackers (similar birthdays)

Expectation management of EMRP

- Extremely difficult to develop new ideas to working prototype in 3 years
- Bigger impact takes longer to achieve
- Longer projects better

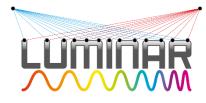


Inter-disciplinary sharing of knowledge

- Surveying, machine tool, robotics, LVM all solving similar problems
- However, previous '1D project' showed these were difficult to combine
- Need to share solutions not issues

Targets

- Auto target finding & coping with line of sight issues
- Look again at targets in photogrammetry passive vs emissive
- Coding: wavelength, radiation pattern, structured beams, fluorescent to give temperature at surface





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